

International Microwave Symposium

11-16 June 2023, San Diego, CA



FASTER MODULATION TESTING IN CHARACTERIZATION AND PRODUCTION

Markus Loerner, Market Segment Manager RF Components

ROHDE&SCHWARZ

Make ideas real



FASTER MODULATION TESTING

13:30 - 13:45

TUMA17: Faster Modulation Testing in Characterization and Production

Speaker: Markus Loerner

Speaker organization: Rohde & Schwarz **Location:** MicroApps Theater, Booth 2447

Abstract:

Rohde & Schwarz is known for high end solutions in Research and Development. But characterization and production has its own rules with much more focus on speed and parallel testing.

This session is about translating R&D performance into high speed and parallel test applications while maintaining standard compliant test scenarios for the latest mobile communication standards.

FROM DEVELOPMENT TO PRODUCTION

Sustomer Value Chain

Summary of objective of RF component manufacturer

Development / prototyping

Characterization / Design Verification

Production

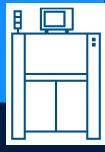
- From Simulation to hardware
- Measurement aided design (e.g. optimization)
- Access to best possible test tools



- Extended verification of specification over small lots & different working conditions
- ► Balance/mixture of speed and performance



- ► Verify product quality
- Very much dependent on product type, target deployment and end customer requirements
- Speed and cost of test is king



FROM DEVELOPMENT TO PRODUCTION

Value Chain

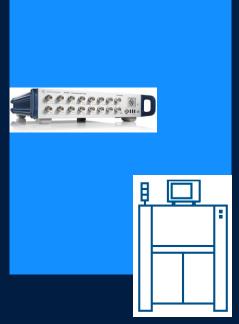
Summary of objective of RF component manufacturer **Development /** prototyping

Characterization / **Design Verification**

Production



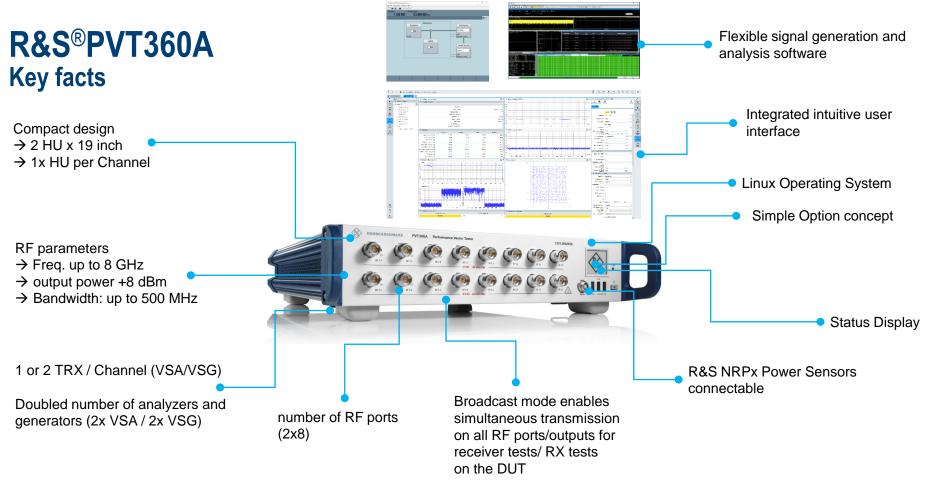






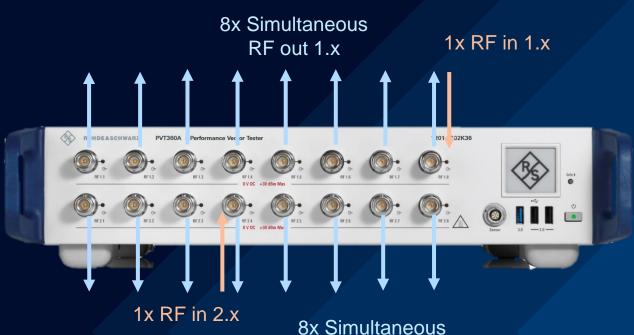
R&S®PVT360A

- Combined Vector signal generator and analyzer in one instrument x 2
- Ideal component testing and for base station
- Up to 8 GHz
- Multi-port operation
- 500 MHz signal bandwidth
- Dedicated measurement and signal generation applications
- Great EVM performance
- Very fast sequential measurements





SWITCH MATRIX



8x Simultaneous RF out 2.x

SMART CHANNELS

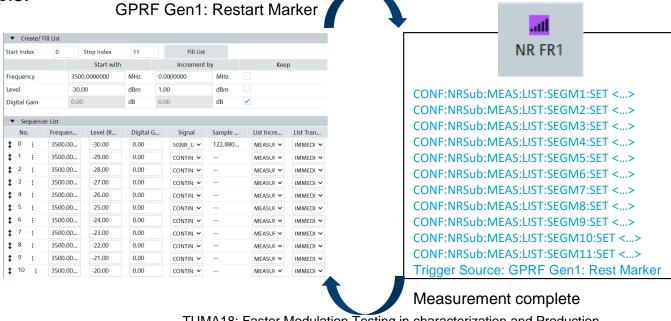


Integrated Sequencing for high speed testing

Store waveform files in the RAM

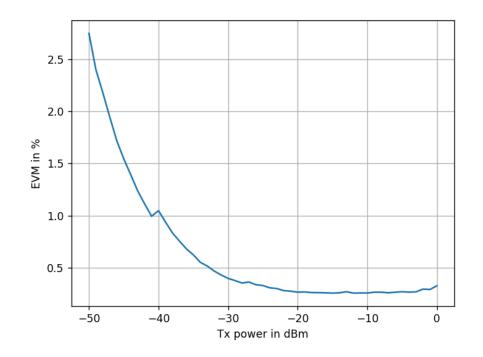
List increments of ARB Sequencer and meas, personality can be internally synchronized

Example:



Integrated Sequencing for high speed testing

- ► 51 segment (power sweep)
 - 3 subframes captured each
 - 1 slot of first subframe analyzed
- ► Total execution time: approx. only 1 sec. !



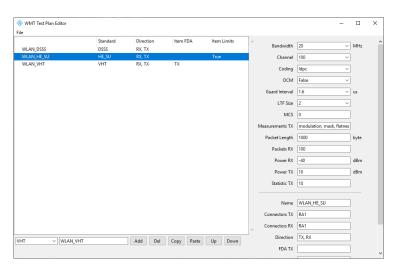
The PVT360A Performance Vector Tester a closer look

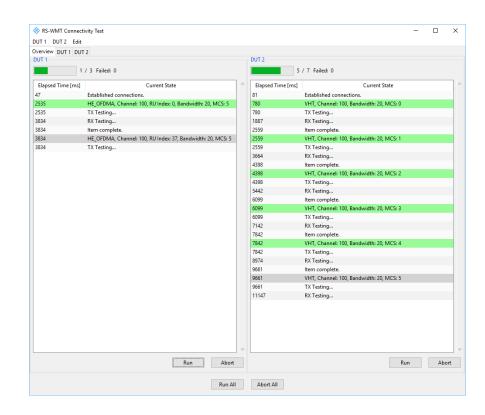
- ▶ Signal generation and analysis for 4G, 5G, Wi-Fi up to 802.11be, BT
- ▶ Supported RF measurements: IP3, harmonics, spurs, ACLR, SEM, EVM, gain, gain compression, ...
- ► Fully supported by
 - R&S WinIQSIM2 signal creation software
 - R&S VSE analysis software in Q2/23
- ▶ Use of NRP sensors for calibration and accurate power measurements
- Integrated Sequencing



WMT – Wireless Manufacturing Test

- ► R&S sequencing software
- ► Modular architecture for flexible integration and minimum time-to-market







PVT360A Performance Vector TesterSummary

- ▶ Maximized speed
- ► Minimized cost per test
- ► Fully automated setups
- ▶ Parallelized testing
- Integration into SW environment
- Correlation between characterization and production setup



